

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S39	310	257/500.ccls. and @ad<"20030416"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/28 04:04
S40	501	(257/395-397).ccls. and @ad<"20030416"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/28 04:12
S41	1055	257/350.ccls. and @ad<"20030416"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/28 04:18
S42	65	257/E29.26.ccls. and @ad<"20030416"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/28 04:47
S44	1335	semiconductor and (high adj voltage) and (low adj voltage) and ((recess or groove or trench or LOCOS) same (edge or bird\$5 or beak)) and (isolation or insulat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/28 05:09
S45	221	semiconductor and (high adj voltage) and (low adj voltage) and ((recess or groove or trench or LOCOS) same ((edge or bird or beak) with (exten\$4 or protr\$5 or project\$3 or bump\$4))) and (isolation or insulat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/28 05:23
S46	606	semiconductor and (high adj voltage) and (low adj voltage) and ((recess or groove or trench or LOCOS) same (edge or bird or beak)) and (step) and @ad<"20030216"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/28 05:40